

PCN Number:	PCN20130904000		PCN Date:	09/05/2013
Title:	Aizu Facility as an additional FAB source for select devices in the F05 Process			
Customer Contact:	PCN Manager	Phone:	+1(214)480-6037	Dept: Quality Services
Proposed 1st Ship Date:	12/05/2013	Estimated Sample Availability:	Date provided at sample request.	
Change Type:	<input type="checkbox"/> Assembly Site <input type="checkbox"/> Assembly Process <input type="checkbox"/> Assembly Materials <input type="checkbox"/> Design <input type="checkbox"/> Electrical Specification <input type="checkbox"/> Mechanical Specification <input type="checkbox"/> Test Site <input type="checkbox"/> Packing/Shipping/Labeling <input type="checkbox"/> Test Process <input type="checkbox"/> Wafer Bump Site <input type="checkbox"/> Wafer Bump Material <input type="checkbox"/> Wafer Bump Process <input checked="" type="checkbox"/> Wafer Fab Site <input type="checkbox"/> Wafer Fab Materials <input type="checkbox"/> Wafer Fab Process <input type="checkbox"/> Part number change			

PCN Details

Description of Change:

This notification is to announce AIZU fabrication facility as an additional wafer FAB source for select devices in the F05 Process. The affected devices are listed in "Product Affected" section.

Currently Qualified Sites, Process, Wafer Dia.	Additional Site, Process, Wafer Dia.
DM5, F05 Process, 200mm	AIZU, F05 Process, 200mm

The F05 process was qualified in Aizu in June 2012. Qualification details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current

Chip Site	Chip site code (20L)	Chip country code (21L)
DP1DM5	DM5	USA

Additional

Chip Site	Chip site code (20L)	Chip country code (21L)
AIZU	CU2	JPN

Sample product shipping label (not actual product label)

 TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 2Q:	 G4		(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483S12 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO:MLA (23L) AOO:MYS				
<table border="1"> <tr> <td>MSL 2 / 260C / 1 YEAR</td> <td>SEAL DT</td> </tr> <tr> <td>MSL 1 / 235C / UNLIM</td> <td>03/29/04</td> </tr> </table>	MSL 2 / 260C / 1 YEAR	SEAL DT	MSL 1 / 235C / UNLIM	03/29/04	OPT: 39 ITEM: LBL: 5A (L)T0:1750		
MSL 2 / 260C / 1 YEAR	SEAL DT						
MSL 1 / 235C / UNLIM	03/29/04						

Product Affected:			
SM02028APTT	TMS320F28021PTT	TMS320F28023DAT	TMS320F280270DAT
SM28020PTT	TMS320F280220DAS	TMS320F28023PTS	TMS320F280270PTS
SM28021PTT	TMS320F280220DAT	TMS320F28023PTT	TMS320F280270PTT
TJF026PTT	TMS320F280220PTS	TMS320F280260DAS	TMS320F28027DAS
TMS320F280200DAS	TMS320F280220PTT	TMS320F280260DAT	TMS320F28027DASR
TMS320F280200DAT	TMS320F28022DAS	TMS320F280260PTS	TMS320F28027DAT
TMS320F280200PTS	TMS320F28022DAT	TMS320F280260PTT	TMS320F28027DATR
TMS320F280200PTT	TMS320F28022PTS	TMS320F28026DAS	TMS320F28027FPTT
TMS320F28020DAS	TMS320F28022PTR	TMS320F28026DASR	TMS320F28027PTR
TMS320F28020DAT	TMS320F28022PTT	TMS320F28026DAT	TMS320F28027PTS
TMS320F28020PTS	TMS320F280230DAS	TMS320F28026DATR	TMS320F28027PTT
TMS320F28020PTT	TMS320F280230DAT	TMS320F28026FPTT	TMS320F28KNW MX1
TMS320F28021DAS	TMS320F280230PTS	TMS320F28026PTS	TMS320SPC0200PTT
TMS320F28021DAT	TMS320F280230PTT	TMS320F28026PTT	
TMS320F28021PTS	TMS320F28023DAS	TMS320F280270DAS	

Qualification Data: Approved 8/30/2013

This qualification has been developed for the validation of this change. The qualification data will validate that the proposed change meets the applicable released technical specifications.

Qual Vehicle 1: TMS320F2802XAPT

Wafer Fab Site:	AIZU	Metallization:	TiN/AlCu/TiN
Wafer Fab Process:	F05	Wafer diameter:	200mm

Qualification: Plan Test Results

Reliability Test	Conditions	Sample Size/Fail		
		Lot #1	Lot #2	Lot #3
Preconditioning	MSL2/260C	540/0	-	-
*Temp Cycle	-65C/150C 500 Cycles (actual 1000 cycles)	231/0	-	-
*Autoclave	121C/96hrs (actual 168 hours)	231/0	-	-

Notes: * Test requires Moisture Preconditioning
Qualification tests "pass" on zero fails for each test

Qual Vehicle 2: TMS320F2802XADA

Wafer Fab Site:	AIZU	Metallization:	TiN/AlCu/TiN
Wafer Fab Process:	F05	Wafer diameter:	200mm

Qualification: Plan Test Results

Reliability Test	Conditions	Sample Size/Fail		
		Lot #1	Lot #2	Lot #3
Preconditioning	MSL2/260C	720/0	-	-
*Temp Cycle	-65C/150C 500 Cycles(actual 750 cycles)	231/0	-	-
*Autoclave	121C/96hrs (actual 168 hours)	231/0	-	-
*High Temp Storage Life	150C, 500 hours	231/0	-	-
ESD-HBM	2000v	3/0	-	-
ESD-CDM	750v	3/0	-	-
Latchup	1.5Vdd +/-100mA 125C	6/0	-	-

Notes: * Test requires Moisture Preconditioning
Qualification tests "pass" on zero fails for each test

Reference Qual: F05 Process Qualification at Aizu

Qualification Data: Approved 06/2012				
This qualification has been developed for the validation of this change. The qualification data will validate that the proposed change meets the applicable released technical specifications.				
Qual Vehicle 1: TMS320F2803XAPN				
Wafer Fab Site:	AIZU	Metallization:	TiN/AICu/TiN	
Wafer Fab Process:	F05	Wafer diameter:	200mm	
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results				
Reliability Test	Conditions	Sample Size/Fail		
		Lot#1	Lot#2	Lot#3
20K W/E	20K Write / Erase Cycles prior to HTSL, HTOL, RTSL	1800/0	-	-
High Temperature Op Life	125C - 1000 Hours	231/0	-	-
*High Temp Storage Life	150C Bake - 1000 Hours	231/0	-	-
Room Temp Storage Life	25C - 1000 Hours	231/0	-	-
Package Reliability			-	-
*Preconditioning	MSL3/260C	693/0	-	-
*THB	85C/85RH	231/0	-	-
*Temp Cycle	-65C/150C 500 Cycles	231/0	-	-
*Autoclave	121C/96hrs	231/0	-	-
ESD-HBM	2000v	15/0	-	-
ESD-CDM	750v	6/0	-	-
Latch up	1.5Vdd +/-100mA 125C	6/0	-	-
Notes: * Test requires Moisture Preconditioning Qualification tests "pass" on zero fails for each test				

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com